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Kind regards,

Team Nexperia

# INTEGRATED CIRCUITS



Product specification Supersedes data of 1998 Feb 13 IC23 Data Handbook

1999 Oct 18



## 74ALVT16373

## **FEATURES**

- 16-bit transparent latch
- 5V I/O compatibile
- 3-State buffers
- Output capability: +64mA/-32mA
- TTL input and output switching levels
- Input and output interface capability to systems at 5V supply
- Bus-hold data inputs eliminate the need for external pull-up resistors to hold unused inputs
- Live insertion/extraction permitted

QUICK REFERENCE DATA

- Power-up reset
- Power-up 3-State
- No bus current loading when output is tied to 5V bus
- Latch-up protection exceeds 500mA per JEDEC Std 17
- ESD protection exceeds 2000V per MIL STD 883 Method 3015 and 200V per Machine Model

## DESCRIPTION

The 74ALVT16373 is a high-performance BiCMOS product designed for  $V_{CC}$  operation at 2.5V or 3.3V with I/O compatibility up to 5V.

This device is a 16-bit transparent D-type latch with non-inverting 3-State bus compatible outputs. The device can be used as two 8-bit latches or one 16-bit latch. When latch enable (LE) input is High, the Q outputs follow the data (D) inputs. When latch enable is taken Low, the Q outputs are latched at the levels of the D inputs one setup time prior to the High-to-Low transition.

SYMPOL	PARAMETER	CONDITIONS	TYPI	UNIT	
SYMBOL	PARAMETER	T <sub>amb</sub> = 25°C	2.5V	3.3V	UNIT
t <sub>PLH</sub> t <sub>PHL</sub>	Propagation delay nDx to nQx	C <sub>L</sub> = 50pF	2.0 2.4	1.6 1.8	ns
C <sub>IN</sub>	Input capacitance	$V_I = 0V \text{ or } V_{CC}$	3	3	pF
C <sub>OUT</sub>	Output capacitance	Outputs disabled; $V_0 = 0V \text{ or } 3.0V$	9	9	pF
I <sub>CCZ</sub>	Total supply current	Outputs disabled	40	70	μΑ

#### **ORDERING INFORMATION**

PACKAGES	TEMPERATURE RANGE	OUTSIDE NORTH AMERICA	NORTH AMERICA	DWG NUMBER
48-Pin Plastic SSOP Type III	–40°C to +85°C	74ALVT16373 DL	AV16373 DL	SOT370-1
48-Pin Plastic TSSOP Type II	–40°C to +85°C	74ALVT16373 DGG	AV16373 DGG	SOT362-1

# 74ALVT16373

LOGIC SYMBOL



#### **PIN DESCRIPTION**

PIN NUMBER	SYMBOL	FUNCTION
47, 46, 44, 43, 41, 40, 38, 37, 36, 35, 33, 32, 30, 29, 27, 26	1D0 – 1D7 2D0 – 2D7	Data inputs
2, 3, 5, 6, 8, 9, 11, 12, 13, 14, 16, 17, 19, 20, 22, 23	1Q0 – 1Q7 2Q0 – 2Q7	Data outputs
1, 24	10E, 20E	Output enable inputs (active-Low)
48, 25	1LE, 2LE	Enable inputs (active-High)
4, 10, 15, 21, 28, 34, 39, 45	GND	Ground (0V)
7, 18, 31, 42	V <sub>CC</sub>	Positive supply voltage

## LOGIC SYMBOL (IEEE/IEC)



## **PIN CONFIGURATION**

		_	
10E		48	1LE
1Q0	2	47	1D0
1Q1	3	46	1D1
GND	4	45	GND
1Q2	5	44	1D2
1Q3	6	43	1D3
VCC	7	42	VCC
1Q4	8	41	1D4
1Q5	9	40	1D5
GND	10	39	GND
1Q6	11	38	1D6
1Q7	12	37	1D7
2Q0	13	36	2D0
2Q1	14	35	2D1
GND	15	34	GND
2Q2	16	33	2D2
2Q3	17	32	2D3
VCC	18	31	VCC
2Q4	19	30	2D4
2Q5	20	29	2D5
GND	21	28	GND
2Q6	22	27	2D6
2Q7	23	26	2D7
2 <del>0E</del>	24	25	2LE
	L	sAC	00043

# 74ALVT16373



## **FUNCTION TABLE**

	INPUTS		INTERNAL	OUTPUTS	OPERATING MODE		
nOE	nLE	nDx	REGISTER	nQ0 – nQ7	OPERATING MODE		
L	H H	L H	L H	L H	Enable and read register		
L	$\downarrow$ $\downarrow$	l h	L H	L H	Latch and read register		
L	L	Х	NC	NC	Hold		
H H	L H	X nDx	NC nDx	Z Z	Disable outputs		

H = High voltage level

High voltage level one set-up time prior to the High-to-Low E transition h =

Low voltage level L =

= Low voltage level one set-up time prior to the High-to-Low E transition 1

NC= No change

X = Don't care

Z = High impedance "off" state $\downarrow = High-to-Low E transition$ 

# LOGIC DIAGRAM

## 74ALVT16373

## **ABSOLUTE MAXIMUM RATINGS<sup>1, 2</sup>**

SYMBOL	PARAMETER CONDITIONS		RATING	UNIT
V <sub>CC</sub>	DC supply voltage		-0.5 to +4.6	V
I <sub>IK</sub>	DC input diode current	V <sub>1</sub> < 0	-50	mA
VI	DC input voltage <sup>3</sup>		-0.5 to +7.0	V
I <sub>OK</sub>	DC output diode current	V <sub>O</sub> < 0	-50	mA
V <sub>OUT</sub>	DC output voltage <sup>3</sup>	Output in Off or High state	-0.5 to +7.0	V
		Output in Low state	128	
lout	DC output current	Output in High state	-64	- mA
T <sub>stg</sub>	Storage temperature range		-65 to +150	°C

NOTES:

Stresses beyond those listed may cause permanent damage to the device. These are stress ratings only and functional operation of the 1. device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

The performance capability of a high-performance integrated circuit in conjunction with its thermal environment can create junction 2. The input and output negative voltage ratings may be exceeded if the input and output clamp current ratings are observed.

## **RECOMMENDED OPERATING CONDITIONS**

SYMBOL	PARAMETER	2.5V RAN	GE LIMITS	3.3V RANGE LIMITS		UNIT
STMDOL		MIN	MAX	MIN	MAX	UNIT
V <sub>CC</sub>	DC supply voltage	2.3	2.7	3.0	3.6	V
VI	Input voltage	0	5.5	0	5.5	V
V <sub>IH</sub>	High-level input voltage	1.7		2.0		V
V <sub>IL</sub>	Input voltage		0.7		0.8	V
I <sub>ОН</sub>	High-level output current		-8		-32	mA
lai	Low-level output current		8		32	mA
IOL	Low-level output current; current duty cycle $\leq$ 50%; f $\geq$ 1kHz		24		64	ША
$\Delta t/\Delta v$	Input transition rise or fall rate; Outputs enabled		10		10	ns/V
T <sub>amb</sub>	Operating free-air temperature range	-40	+85	-40	+85	°C

## 74ALVT16373

## DC ELECTRICAL CHARACTERISTICS (3.3V $\pm$ 0.3V RANGE)

					LIMITS		
SYMBOL	PARAMETER	TEST CONDITIONS	TEST CONDITIONS		-40°C to	+85°C	UNIT
				MIN	TYP <sup>1</sup>	MAX	
VIK	Input clamp voltage	$V_{CC} = 3.0V; I_{IK} = -18mA$			-0.85	-1.2	V
Maria	High-level output voltage	$V_{CC} = 3.0$ to 3.6V; $I_{OH} = -100\mu A$		V <sub>CC</sub> -0.2	V <sub>CC</sub>		v
V <sub>OH</sub>	High-level output voltage	V <sub>CC</sub> = 3.0V; I <sub>OH</sub> = -32mA		2.0	2.3		Ň
		V <sub>CC</sub> = 3.0V; I <sub>OL</sub> = 100µA			0.07	0.2	
Vol	Low-level output voltage	V <sub>CC</sub> = 3.0V; I <sub>OL</sub> = 16mA			0.25	0.4	v
VOL		$V_{CC} = 3.0V; I_{OL} = 32mA$			0.3	0.5	Ň
		$V_{CC} = 3.0V; I_{OL} = 64mA$			0.4	0.55	
V <sub>RST</sub>	Power-up output low voltage <sup>6</sup>	$V_{CC}$ = 3.6V; $I_{O}$ = 1mA; $V_{I}$ = $V_{CC}$ or GND				0.55	V
		$V_{CC} = 3.6V; V_I = V_{CC} \text{ or } GND$	Control pins		0.1	±1	
L	Input lookage ourrept	$V_{CC} = 0 \text{ or } 3.6 \text{V}; \text{ V}_{\text{I}} = 5.5 \text{V}$			0.1	10	
η	IIIIIIIIIIIIIIIIIIIIIIIIIIIIIIIIIIIIII	$V_{CC} = 3.6V; V_{I} = V_{CC}$	Data pins <sup>4</sup>		0.5	1	μA
		$V_{CC} = 3.6V; V_{I} = 0V$	Data pins		0.1	-5	
I <sub>OFF</sub>	Off current	$V_{CC} = 0V; V_{I} \text{ or } V_{O} = 0 \text{ to } 4.5V$			0.1	±100	μΑ
	Bus Hold current	$V_{CC} = 3V; V_I = 0.8V$		75	130		
I <sub>HOLD</sub>	Data inputs <sup>7</sup>	$V_{CC} = 3V; V_{I} = 2.0V$		-75	-140		μA
	Data inputs	$V_{CC} = 0V$ to 3.6V; $V_{CC} = 3.6V$		±500			
$I_{EX}$	Current into an output in the High state when $V_O > V_{CC}$	V <sub>O</sub> = 5.5V; V <sub>CC</sub> = 3.0V			10	125	μΑ
I <sub>PU/PD</sub>	Power up/down 3-State output current <sup>3</sup>	$V_{CC} \le 1.2$ V; $V_O = 0.5$ V to $V_{CC}$ ; $V_I = GND OE/OE = Don't care$	) or V <sub>CC</sub> ;		1	±100	μA
I <sub>OZH</sub>	3-State output High current	$V_{CC} = 3.6V; V_O = 3.0V; V_I = V_{IL} \text{ or } V_{IH}$			0.5	5	μΑ
I <sub>OZL</sub>	3-State output Low current	$V_{CC} = 3.6V; V_{O} = 0.5V; V_{I} = V_{IL} \text{ or } V_{IH}$			0.5	-5	μΑ
ICCH		$V_{CC} = 3.6V$ ; Outputs High, $V_I = GND$ or $V_{CC}$ , $I_O = 0$			0.04	0.1	
I <sub>CCL</sub>	Quiescent supply current	$V_{CC} = 3.6V$ ; Outputs Low, $V_I = GND$ or $V_{CC}$ , $I_{O} = 0$			3.5	5 mA	
I <sub>CCZ</sub>	1	V <sub>CC</sub> = 3.6V; Outputs Disabled; V <sub>I</sub> = GND	) or $V_{CC}$ , $I_{O} = 0^5$		0.05	0.1	0.1
$\Delta I_{CC}$	Additional supply current per input pin <sup>2</sup>	$V_{CC} = 3V$ to 3.6V; One input at $V_{CC}$ -0.6° Other inputs at $V_{CC}$ or GND	V,		0.04	0.4	mA

NOTES:

All typical values are at V<sub>CC</sub> = 3.3V and T<sub>amb</sub> = 25°C.
This is the increase in supply current for each input at the specified voltage level other than V<sub>CC</sub> or GND
This parameter is valid for any V<sub>CC</sub> between 0V and 1.2V with a transition time of up to 10msec. From V<sub>CC</sub> = 1.2V to V<sub>CC</sub> = 3.3V ± 0.3V a transition time of 100µsec is permitted. This parameter is valid for T<sub>amb</sub> = 25°C only.
Unused pins at V<sub>CC</sub> or GND.

I<sub>CCZ</sub> is measured with outputs pulled up to V<sub>CC</sub> or pulled down to ground.
For valid test results, data must not be loaded into the flip-flops (or latches) after applying power.

7. This is the bus hold overdrive current required to force the input to the opposite logic state.

## AC CHARACTERISTICS (3.3V $\pm$ 0.3V RANGE)

GND = 0V;  $t_R = t_F = 2.5ns$ ;  $C_L = 50pF$ ;  $R_L = 500\Omega$ ;  $T_{amb} = -40^{\circ}C$  to +85°C.

SYMBOL	PARAMETER	WAVEFORM	Vc	$_{\rm C} = 3.3 V \pm 0.$	.3V	UNIT
			MIN	TYP <sup>1</sup>	MAX	
t <sub>PLH</sub> t <sub>PHL</sub>	Propagation delay nDx to nQx	2	0.5 0.5	1.6 1.8	2.5 2.9	ns
t <sub>PLH</sub> t <sub>PHL</sub>	Propagation delay nLE to nQx	1	1.0 1.0	2.0 2.3	3.1 3.3	ns
t <sub>PZH</sub> t <sub>PZL</sub>	Output enable time to High and Low level	4 5	1.5 1.0	2.3 1.9	4.0 3.1	ns
t <sub>PHZ</sub> t <sub>PLZ</sub>	Output disable time from High and Low Level	4 5	1.5 1.5	2.9 2.3	4.5 3.7	ns

NOTE:

1. All typical values are at  $V_{CC}$  = 3.3V and  $T_{amb}$  = 25°C.

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## DC ELECTRICAL CHARACTERISTICS (2.5V ±0.2V RANGE)

					LIMITS		
SYMBOL	PARAMETER	TEST CONDITIONS		Temp =	+85°C	UNIT	
				MIN	TYP <sup>1</sup>	MAX	1
VIK	Input clamp voltage	$V_{CC} = 2.3V; I_{IK} = -18mA$			-0.85	-1.2	V
V <sub>OH</sub>	High-level output voltage	$V_{CC} = 2.3$ to 3.6V; $I_{OH} = -100\mu A$		V <sub>CC</sub> -0.2			v
VОН	riigh-level output voltage	$V_{CC} = 2.3V; I_{OH} = -8mA$		1.8			v
V <sub>OL</sub>	Low-level output voltage	$V_{CC} = 2.3V; I_{OL} = 100\mu A$			0.07	0.2	
VOL	Low-level output voltage	$V_{CC} = 2.3V; I_{OL} = 24mA$			0.3	0.5	
V <sub>RST</sub>	Power-up output low voltage <sup>7</sup>	$V_{CC} = 2.7V; I_O = 1mA; V_I = V_{CC} \text{ or GND}$				0.55	V
		$V_{CC} = 2.7V; V_I = V_{CC}$ or GND	Control pins		0.1	±1	
	Input leakage current	$V_{CC} = 0 \text{ or } 2.7 \text{V}; \text{ V}_{I} = 5.5 \text{V}$			0.1	10	
łı	input leakage current	$V_{CC} = 2.7V; V_{I} = V_{CC}$	$V_{CC} = 2.7V; V_I = V_{CC}$		0.1	1	μA
		$V_{CC} = 2.7V; V_I = 0$ Data pins <sup>4</sup>			0.1	-5	1
I <sub>OFF</sub>	Off current	$V_{CC} = 0V$ ; $V_I$ or $V_O = 0$ to 4.5V	-		0.1	±100	μΑ
I <sub>HOLD</sub>	Bus Hold current	$V_{CC} = 2.3V; V_I = 0.7V$			90		μA
-	Data inputs <sup>6</sup>	$V_{CC} = 2.3V; V_I = 1.7V$			-10		μΛ
$I_{EX}$	Current into an output in the High state when $V_O > V_{CC}$	$V_{O} = 5.5V; V_{CC} = 2.3V$			10	125	μA
I <sub>PU/PD</sub>	Power up/down 3-State output current <sup>3</sup>	$V_{CC} \le 1.2$ V; $V_{O} = 0.5$ V to $V_{CC}$ ; $V_{I} = GNE$ OE/OE = Don't care	) or V <sub>CC</sub> ;		1	100	μA
I <sub>OZH</sub>	3-State output High current	$V_{CC} = 2.7V; V_{O} = 2.3V; V_{I} = V_{IL} \text{ or } V_{IH}$			0.5	5	μA
I <sub>OZL</sub>	3-State output Low current	$V_{CC} = 2.7V; V_{O} = 0.5V; V_{I} = V_{IL} \text{ or } V_{IH}$			0.5	-5	μA
I <sub>CCH</sub>		$V_{CC} = 2.7V$ ; Outputs High, $V_{I} = GND$ or	V <sub>CC</sub> , I <sub>O =</sub> 0		0.04	0.1	
I <sub>CCL</sub>	Quiescent supply current	$V_{CC} = 2.7V$ ; Outputs Low, $V_I = GND$ or $V_{CC}$ , $I_O = 0$			2.3	4.5	mA
I <sub>CCZ</sub>	1	$V_{CC}$ = 2.7V; Outputs Disabled; $V_I$ = GNE		0.04	0.1	1	
$\Delta I_{CC}$	Additional supply current per input pin <sup>2</sup>	$V_{CC}$ = 2.3V to 2.7V; One input at $V_{CC}$ -0 Other inputs at $V_{CC}$ or GND	.6V,		0.04	0.4	mA

NOTES:

1. All typical values are at  $V_{CC} = 2.5V$  and  $T_{amb} = 25^{\circ}C$ . 2. This is the increase in supply current for each input at the specified voltage level other than  $V_{CC}$  or GND 3. This parameter is valid for any  $V_{CC}$  between 0V and 1.2V with a transition time of up to 10msec. From  $V_{CC} = 1.2V$  to  $V_{CC} = 2.5V \pm 0.2V$  a transition time of  $100\mu$ sec is permitted. This parameter is valid for  $T_{amb} = 25^{\circ}C$  only. 4. Unused pins at V<sub>CC</sub> or GND.

5.  $I_{CCZ}$  is measured with outputs pulled up to  $V_{CC}$  or pulled down to ground.

6. Not guaranteed.

7. For valid test results, data must not be loaded into the flip-flops (or latches) after applying power.

## AC CHARACTERISTICS (2.5V $\pm$ 0.2V RANGE)

GND = 0V;  $t_R = t_F = 2.5ns$ ;  $C_L = 50pF$ ;  $R_L = 500\Omega$ ;  $T_{amb} = -40^{\circ}C$  to +85°C.

SYMBOL	PARAMETER	WAVEFORM	V <sub>C</sub>	$c = 2.5V \pm 0.00$	.2V	UNIT
			MIN	TYP <sup>1</sup>	MAX	
t <sub>PLH</sub> t <sub>PHL</sub>	Propagation delay nDx to nQx	2	1.0 1.0	2.0 2.4	3.2 4.2	ns
t <sub>PLH</sub> t <sub>PHL</sub>	Propagation delay nLE to nQx	1	1.5 1.5	2.6 2.8	4.2 4.5	ns
t <sub>PZH</sub> t <sub>PZL</sub>	Output enable time to High and Low level	4 5	2.0 1.5	3.5 2.6	5.5 4.7	ns
t <sub>PHZ</sub> t <sub>PLZ</sub>	Output disable time from High and Low Level	4 5	1.5 1.0	2.7 2.0	4.5 3.5	ns

NOTE:

1. All typical values are at V<sub>CC</sub> = 2.5V and T<sub>amb</sub> = 25°C.

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## AC SETUP REQUIREMENTS

GND = 0V;  $t_R = t_F = 2.5ns$ ;  $C_L = 50pF$ ;  $R_L = 500\Omega$ ;  $T_{amb} = -40^{\circ}C$  to +85°C.

				LIM	ITS		
SYMBOL	PARAMETER	WAVEFORM	V <sub>CC</sub> = 2.	5V ±0.2V	V <sub>CC</sub> = 3.3	3V ±0.3V	UNIT
			MIN	TYP	MIN	TYP	
t <sub>S</sub> (H) t <sub>S</sub> (L)	Setup time nDx to nLE	3	0 1.5	0.7 0.2	0.5 0.8	-0.2 0.2	ns
t <sub>h</sub> (H) t <sub>h</sub> (L)	Hold time nDx to nLE	3	0.5 1.5	-0.2 0.7	0.8 1.0	0 0.2	ns
t <sub>W</sub> (H)	nLE pulse width High	1	1.5 1.5		1.5 1.5		ns

## AC WAVEFORMS

For all waveforms

 $\begin{array}{l} V_{M} = 1.5V \; \text{for} \; V_{CC} \geq 3.0V; \; V_{M} = V_{CC}/2 \; \text{for} \; V_{CC} \leq 2.7V \\ V_{M} = 1.5V \; \text{for} \; V_{CC} \geq 3.0V; \; V_{M} = V_{CC}/2 \; \text{for} \; V_{CC} \leq 2.7V \\ V_{X} = V_{OL} + 0.3V \; \text{for} \; V_{CC} \; \geq 3.0V; \; V_{X} = V_{OL} + 0.15V \; \text{for} \; V_{CC} \leq 2.7V \\ V_{Y} = V_{OH} - 0.3V \; \text{for} \; V_{CC} \; \geq 3.0V; \; V_{Y} = V_{OH} - 0.15V \; \text{for} \; V_{CC} \leq 2.7V \\ V_{Y} = V_{OH} - 0.3V \; \text{for} \; V_{CC} \; \geq 3.0V; \; V_{Y} = V_{OH} - 0.15V \; \text{for} \; V_{CC} \leq 2.7V \\ \end{array}$ 



Waveform 1. Propagation Delay, Enable to Output, and Enable Pulse Width



Waveform 2. Propagation Delay for Data to Outputs



Waveform 3. Data Setup and Hold Times



Waveform 4. 3-State Output Enable time to High Level and Output Disable Time from High Level



Waveform 5. 3-State Output Enable Time to Low Level and Output Disable Time from Low Level

## 74ALVT16373

## **TEST CIRCUIT AND WAVEFORMS**



## 74ALVT16373



OUTLINE	INE REFERENCES					ISSUE DATE
VERSION	IEC	JEDEC	EIAJ		PROJECTION	ISSUE DATE
SOT370-1		MO-118AA				<del>-93-11-02-</del> 95-02-04

## 74ALVT16373



OUTLINE	OUTLINE REFERENCES				EUROPEAN	ISSUE DATE
VERSION	IEC	JEDEC	EIAJ		PROJECTION	ISSUE DATE
SOT362-1		MO-153ED				<del>- 93-02-03</del> 95-02-10
					- +	00 02 10

# 74ALVT16373

#### Data sheet status

Data sheet status	Product status	Definition [1]
Objective specification	Development	This data sheet contains the design target or goal specifications for product development. Specification may change in any manner without notice.
Preliminary specification	Qualification	This data sheet contains preliminary data, and supplementary data will be published at a later date. Philips Semiconductors reserves the right to make changes at any time without notice in order to improve design and supply the best possible product.
Product specification	Production	This data sheet contains final specifications. Philips Semiconductors reserves the right to make changes at any time without notice in order to improve design and supply the best possible product.

[1] Please consult the most recently issued datasheet before initiating or completing a design.

#### Definitions

Short-form specification — The data in a short-form specification is extracted from a full data sheet with the same type number and title. For detailed information see the relevant data sheet or data handbook.

Limiting values definition - Limiting values given are in accordance with the Absolute Maximum Rating System (IEC 134). Stress above one or more of the limiting values may cause permanent damage to the device. These are stress ratings only and operation of the device at these or at any other conditions above those given in the Characteristics sections of the specification is not implied. Exposure to limiting values for extended periods may affect device reliability.

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**Philips Semiconductors** 811 East Arques Avenue P.O. Box 3409 Sunnyvale, California 94088-3409 Telephone 800-234-7381

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